

Data sheet acquired from Harris Semiconductor SCHS192B

# CD54HC640, CD74HC640, CD54HCT640, CD74HCT640

# High-Speed CMOS Logic Octal Three-State Bus Transceiver, Inverting

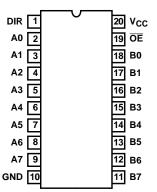
January 1998 - Revised May 2003

#### Features

- · Buffered Inputs
- · Three-State Outputs
- Applications in Multiple-Data-Bus Architecture
- Fanout (Over Temperature Range)
  - Standard Outputs...... 10 LSTTL Loads
  - Bus Driver Outputs ...... 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
  - 2V to 6V Operation
  - High Noise Immunity:  $N_{IL}$  = 30%,  $N_{IH}$  = 30% of  $V_{CC}$  at  $V_{CC}$  = 5V
- HCT Types
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility,
     V<sub>IL</sub>= 0.8V (Max), V<sub>IH</sub> = 2V (Min)
  - CMOS Input Compatibility, I<sub>I</sub>  $\leq$  1 $\mu$ A at V<sub>OL</sub>, V<sub>OH</sub>

#### **Pinout**

CD54HC640, CD54HCT640 (CERDIP) CD74HC640, CD74HCT640 (PDIP, SOIC) TOP VIEW



# Description

The 'HC640 and 'HCT640 silicon-gate CMOS three-state bidirectional inverting and non-inverting buffers are intended for two-way asynchronous communication between data buses. They have high drive current outputs which enable high-speed operation when driving large bus capacitances. These circuits possess the low power dissipation of CMOS circuits, and have speeds comparable to low power Schottky TTL circuits. They can drive 15 LSTTL loads. The 'HC640 and 'HCT640 are inverting buffers.

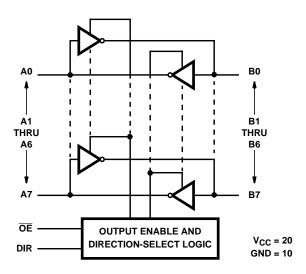
The direction of data flow (A to B, B to A) is controlled by the DIR input.

Outputs are enabled by a low on the Output Enable input  $(\overline{OE})$ ; a high  $\overline{OE}$  puts these devices in the high impedance mode.

# **Ordering Information**

PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC640F3A	-55 to 125	20 Ld CERDIP
CD54HCT640F3A	-55 to 125	20 Ld CERDIP
CD74HC640E	-55 to 125	20 Ld PDIP
CD74HC640M	-55 to 125	20 Ld SOIC
CD74HCT640E	-55 to 125	20 Ld PDIP
CD74HCT640M	-55 to 125	20 Ld SOIC

# Functional Diagram



#### **TRUTH TABLE**

CONTRO	L INPUTS	DATA PORT STATUS				
ŌĒ	DIR	A <sub>n</sub>	B <sub>n</sub>			
L	L	Ō	I			
Н	Н	Z	Z			
Н	L	Z	Z			
L	Н	I	Ō			

To prevent excess currents in the High-Z modes all I/O terminals should be terminated with 1k $\Omega$  to 1M $\Omega$  resistors.

H = High Level

L = Low Level

I = Input

 $\overline{O}$  = Output (Inversion of Input Level)

Z = High Impedance

# **Absolute Maximum Ratings**

# DC Supply Voltage, V $_{CC}$ ... -0.5V to 7V DC Input Diode Current, I $_{IK}$ For V $_{I}$ < -0.5V or V $_{I}$ > V $_{CC}$ + 0.5V ... ... $\pm 20$ mA DC Output Diode Current, I $_{OK}$ For V $_{O}$ < -0.5V or V $_{O}$ > V $_{CC}$ + 0.5V ... ... $\pm 20$ mA DC Drain Current, per Output, I $_{O}$ For -0.5V < V $_{O}$ < V $_{CC}$ + 0.5V ... ... $\pm 35$ mA DC Output Source or Sink Current per Output Pin, I $_{O}$ For V $_{O}$ > -0.5V or V $_{O}$ < V $_{CC}$ + 0.5V ... ... $\pm 25$ mA DC V $_{CC}$ or Ground Current, I $_{CC}$ ... $\pm 50$ mA

## **Thermal Information**

Thermal Resistance (Typical, Note 1)	$\theta_{JA}$ (oC/W)
E (PDIP) Package	69
M (SOIC) Package	58
Maximum Junction Temperature	150 <sup>0</sup> C
Maximum Storage Temperature Range	65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300 <sup>o</sup> C
(SOIC - Lead Tips Only)	

# **Operating Conditions**

Temperature Range, T <sub>A</sub> 55°C to 125°C
Supply Voltage Range, V <sub>CC</sub>
HC Types2V to 6V
HCT Types
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub> 0V to V <sub>CC</sub>
Input Rise and Fall Time
2V
4.5V 500ns (Max)
6V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

1. The package thermal impedance is calculated in accordance with JESD 51-7.

# **DC Electrical Specifications**

		TE: CONDI		v <sub>cc</sub>	25°C			-40°C 1	O 85°C	-55°C TO 125°C				
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS		
HC TYPES														
High Level Input	V <sub>IH</sub>	-	-	2	1.5	-	-	1.5	-	1.5	-	V		
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V		
				6	4.2	-	-	4.2	-	4.2	-	V		
Low Level Input	V <sub>IL</sub>	-	-	2	-	-	0.5	-	0.5	-	0.5	V		
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V		
				6	-	-	1.8	-	1.8	-	1.8	V		
High Level Output	VoH	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	2	1.9	-	-	1.9	-	1.9	-	V		
Voltage CMOS Loads			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V		
Ower Education			-0.02	6	5.9	-	-	5.9	-	5.9	-	V		
High Level Output	7				-	-	-	-	-	-	-	-	-	V
Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V		
112 20000			-7.8	6	5.48	-	-	5.34	-	5.2	-	V		
Low Level Output	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	2	-	-	0.1	-	0.1	-	0.1	V		
Voltage CMOS Loads			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V		
Owied Educa			0.02	6	-	-	0.1	-	0.1	-	0.1	V		
Low Level Output	1		-	-	-	-	-	-	-	-	-	V		
Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V		
			7.8	6	-	-	0.26	-	0.33	-	0.4	V		
Input Leakage Current	II	V <sub>CC</sub> or GND	-	6	-	ı	±0.1	-	±1	-	±1	μА		

# DC Electrical Specifications (Continued)

		TEST CONDITIONS		V <sub>CC</sub>	25°C			-40°C TO 85°C		-55°C TO 125°C			
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS	
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	6	-	-	8	-	80	-	160	μΑ	
Three-State Leakage Current	l <sub>OZ</sub>	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	6	-	-	±0.5	-	±5	-	±10	μА	
HCT TYPES	•	•	•					•	•	•			
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V	
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V	
High Level Output Voltage CMOS Loads	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V	
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V	
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V	
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V	
Input Leakage Current	lı	V <sub>CC</sub> and GND	0	5.5	-	-	±0.1	-	±1	-	±1	μА	
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	5.5	-	-	8	-	80	-	160	μΑ	
Three-State Leakage Current	loz	V <sub>IL</sub> or V <sub>IH</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5	-	-	±0.5	-	±5	-	±10	μА	
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI <sub>CC</sub> (Note 2)	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μА	

# NOTE:

# **HCT Input Loading Table**

INPUT	UNIT LOADS
DIR	0.9
ŌĒ, A	1.5
В	1.5

NOTE: Unit Load is  $\Delta I_{CC}$  limit specified in DC Electrical Table, e.g.,  $360\mu A$  max at  $25^{o}C.$ 

<sup>2.</sup> For dual-supply systems theoretical worst case ( $V_I = 2.4V$ ,  $V_{CC} = 5.5V$ ) specification is 1.8mA.

# **Switching Specifications** $C_L = 50pF$ , Input $t_r$ , $t_f = 6ns$

		TEST CONDITIONS		25°C				C TO °C	-55°C TO 125°C		
PARAMETER	SYMBOL		V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES											
Propagation Delay	t <sub>PHL</sub> , t <sub>PLH</sub>	C <sub>L</sub> = 50pF									
A to $\overline{B}$ B to $\overline{A}$			2	-	-	90	-	115	-	135	ns
2.67.1			4.5	-	-	18	-	23	-	27	ns
		C <sub>L</sub> = 15pF	5	-	7	-	-	-	-	-	ns
		$C_L = 50pF$	6	-	-	15	-	20	-	23	ns
Output High-Z	t <sub>PHL</sub> , t <sub>PLH</sub>	$C_L = 50pF$	2	1	-	150	-	190	-	225	ns
To High Level, To Low Level			4.5	-	-	30	-	38	-	45	ns
		C <sub>L</sub> = 15pF	5	-	12	-	-	-	-	-	ns
		C <sub>L</sub> = 50pF	6	-	-	26	-	33	-	38	ns
Output High Level	t <sub>PHZ</sub> , t <sub>PLZ</sub>	C <sub>L</sub> = 50pF	2	-	-	150	-	190	-	225	ns
Output Low Level to High Z			4.5	-	-	30	-	38	-	45	ns
		C <sub>L</sub> = 15pF	5	-	12	-	-	-	-	-	ns
		C <sub>L</sub> = 50pF	6	-	-	26	-	33	-	38	ns
Output Transition Time	t <sub>THL</sub> , t <sub>TLH</sub>	C <sub>L</sub> = 50pF	2	-	-	60	-	75	-	90	ns
			4.5	-	-	12	-	15	-	18	ns
			6	-	-	10	-	13	-	15	ns
Input Capacitance	C <sub>IN</sub>	C <sub>L</sub> = 50pF	-	10	-	10	-	10	-	10	pF
Three-State Output Capacitance	C <sub>O</sub>	-	-	-	-	20	-	20	-	20	pF
Power Dissipation Capacitance (Notes 3, 4)	C <sub>PD</sub>	-	5	-	38	-	-	-	-	-	pF
HCT TYPES	!		!		<u> </u>	<u> </u>			<u> </u>	<u> </u>	
Propagation Delay											
A to B	t <sub>PHL</sub> , t <sub>PLH</sub>	C <sub>L</sub> = 50pF	4.5	-	-	22	-	28	-	33	ns
B to Ā		C <sub>L</sub> = 15pF	5	-	9	-	-	-	-	-	ns
Output High-Z	t <sub>PHL</sub> , t <sub>PLH</sub>	C <sub>L</sub> = 50pF	4.5	-	-	30	-	38	-	45	ns
To High Level, To Low Level		C <sub>L</sub> = 15pF	5	-	12	-	-	-	-	-	ns
Output High Level	t <sub>PHZ,</sub> t <sub>PLZ</sub>	C <sub>L</sub> = 50pF	4.5	_	-	30	_	38	-	45	ns
Output Low Level to High Z		C <sub>L</sub> = 15pF	5	-	12	-	_	-	-	-	ns
Output Transition Time	t <sub>THL</sub> , t <sub>TLH</sub>	C <sub>L</sub> = 50pF	4.5	-	_	12	_	15	_	18	ns
Input Capacitance	C <sub>IN</sub>	C <sub>L</sub> = 50pF	-	10	-	10	-	10	-	10	pF
Three-State Output Capacitance	CO	<u> </u>	-	-	-	20	-	20	-	20	pF
Power Dissipation Capacitance (Notes 3, 4)	C <sub>PD</sub>	-	5	-	41	-	-	-	-	-	pF

#### NOTES:

- 3.  $C_{\mbox{\scriptsize PD}}$  is used to determine the dynamic power consumption, per channel.
- $\text{4. } P_D = \text{V}_{CC}^2 \, f_i \, (\text{C}_{PD} + \text{C}_L) \, \text{where} \, f_i = \text{Input Frequency}, \, C_L = \text{Output Load Capacitance}, \, \text{V}_{CC} = \text{Supply Voltage}.$

# Test Circuits and Waveforms

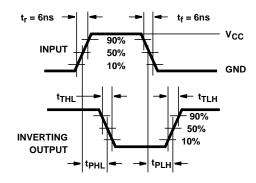


FIGURE 7. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

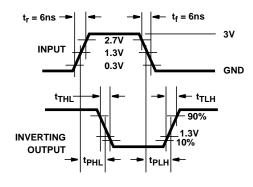


FIGURE 8. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

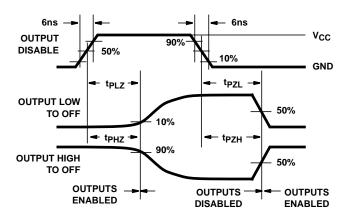


FIGURE 9. HC THREE-STATE PROPAGATION DELAY WAVEFORM

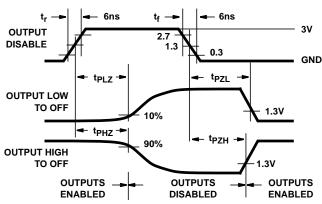
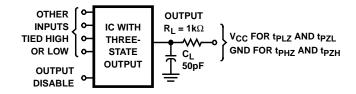


FIGURE 10. HCT THREE-STATE PROPAGATION DELAY WAVEFORM



NOTE: Open drain waveforms  $t_{PLZ}$  and  $t_{PZL}$  are the same as those for three-state shown on the left. The test circuit is Output  $R_L = 1k\Omega$  to  $V_{CC}$ ,  $C_L = 50pF$ .

FIGURE 11. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT

# 14 LEADS SHOWN



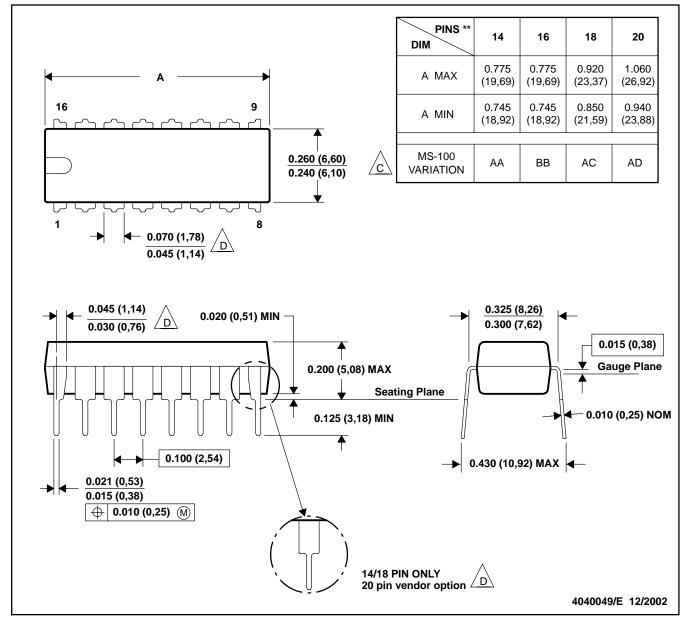
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

# N (R-PDIP-T\*\*)

#### **16 PINS SHOWN**

# PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

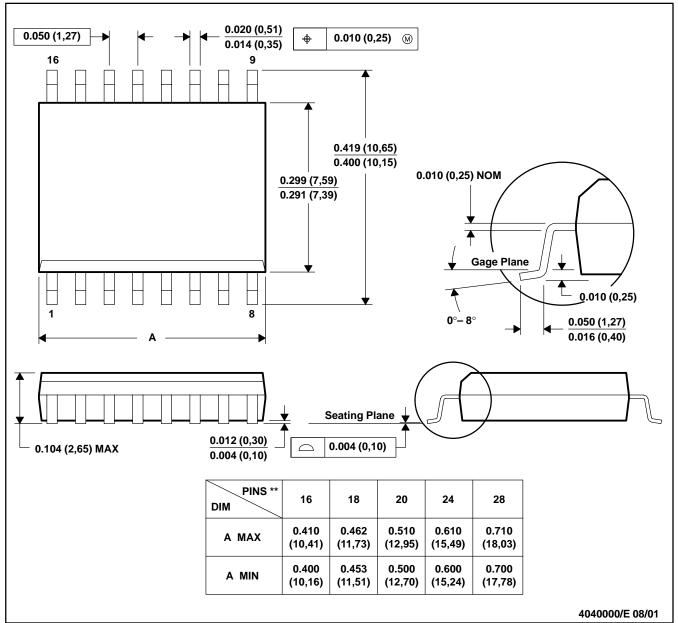
Falls within JEDEC MS-001, except 18 and 20 pin minimum body Irngth (Dim A).

The 20 pin end lead shoulder width is a vendor option, either half or full width.

# DW (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE

## **16 PINS SHOWN**



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013

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